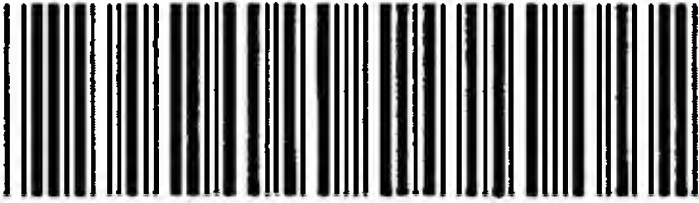


Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/650,852	HIEDA, KATSUHIKO	
	Examiner	Art Unit	
	Edward Wojciechowicz	2815	

SEARCHED			
Class	Subclass	Date	Examiner
257	296	10-20-05	EPH

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
See serial history	10-20-05	EPH